# TOWARDS FUNCTIONAL COVERAGE-DRIVEN FUZZING FOR CHISEL DESIGNS

Andrew Dobis, Tjark Petersen & Martin Schoeberl.

- Technical University of Denmark (DTU) - Department of Applied Mathematics & Computer Science



#### OUTLINE

- ➤ <u>Motivation:</u> Why use Functional Coverage as a metric?
- ➤ <u>Background:</u> Chisel & Fuzzing.
- ➤ <u>Current solutions</u>: Fuzzing for Chisel designs using software fuzzers and using custom hardware fuzzing.
- ➤ <u>Our solution:</u> Use hardware-oriented coverage metric to drive fuzzing of a Chisel Design.
- ➤ <u>Initial Experiments:</u> Using the fuzzer on the Leros accumulator ALU.
- ➤ <u>Note:</u> This solution is a work in progress and is currently still in development.

## MOTIVATION

#### MOTIVATION: WHY USE FUNCTIONAL COVERAGE?

➤ Fuzzing is often associated to software testing.

➤ Current work has been done on Fuzzing for Digital Circuits, but none using **Functional Coverage** as a driving metric.

#### ➤ Goal:

- ➤ **Explore** the effects of using a metric that inherently contains data about the Device Under Test (DUT).
- **Evaluate** its impact on the fuzzing efficiency.

## BACKGROUND

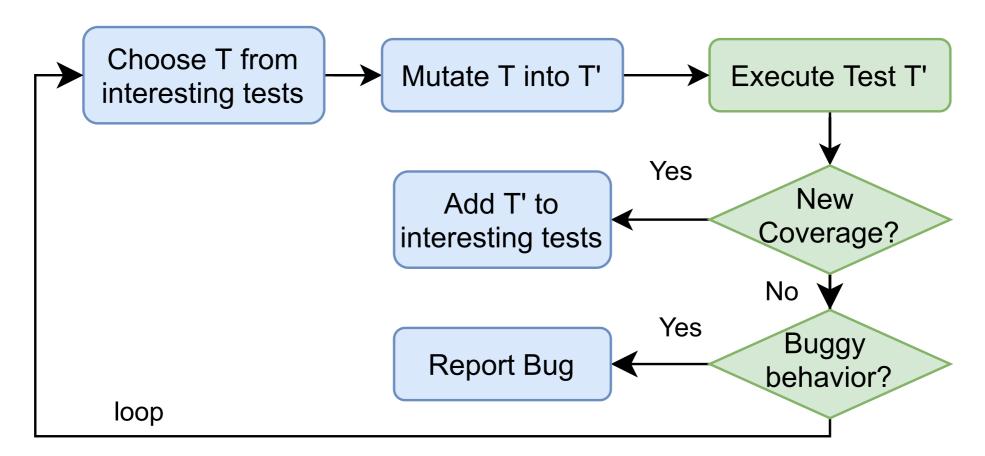
#### **BACKGROUND: CHISEL AND VERIFICATION**

➤ <u>Chisel:</u> Hardware Construction Language (HCL) embedded in Scala. Allows for high-level description of digital circuits using Object-Oriented and Functional programming. Can generate Verilog as a final output.

➤ <u>Functional Coverage</u>: Hardware-centric coverage metric based around the use of a *Verification Plan(VP)*. Functional Coverage gives a quantitative measure of the testing progress, telling us "which features of the DUT have been tested?".

#### BACKGROUND: COVERAGE DRIVEN MUTATION-BASED FUZZING

- ➤ Automatic randomized input generation.
- ➤ Inputs are based on a set of valid initial inputs (seeds).
- ➤ Seeds are then mutated depending on the coverage result that they generate. If the new inputs are "interesting", they are added to the seeds.



## CURRENT SOLUTIONS

#### OVERVIEW OF THE CURRENT SOLUTIONS

- American Fuzzy Lop (AFL), 2013:
  - ➤ Software coverage driven mutation-based fuzzer.
  - uses edge coverage, a form of branch coverage.
  - ➤ Their mutation techniques are used in our solution.
- ➤ RFuzz, 2020:
  - ➤ Coverage-driven mutation based buzzer for RTL designs.
  - ➤ Leverages FPGAs to accelerate their solution.
  - > Employs intelligent techniques for fast memory initialization.
  - Metric is also edge coverage.

#### **CURRENT SOLUTIONS: CONTINUATION**

- ➤ Fuzzing Hardware like Software, 2021:
  - ➤ Translates DUT hardware into a software model.
  - ➤ Uses existing software fuzzers for the fuzzing.

- ➤ All of these solutions rely on the same metric to guide fuzzing.
  - ➤ Why not use a more complex metric?
  - ➤ What will the impact on the performance look like?

### OUR SOLUTION: FUNCTIONAL COVERAGE TO DRIVE FUZZING

#### **OUR SOLUTION: OVERVIEW**

- ➤ Functional Coverage metric being used is from ChiselVerify.
- ➤ Fuzzer functions in 5 phases:
  - ➤ **Interpret** user-defined input files as bit-streams and load them into the queue.
  - > Select next file from queue.
  - ➤ **Mutate** file, first with deterministic then nondeterministic mutation passes.
  - > Run test and retrieve coverage results.
  - ➤ Compare results to previous ones, determine if test was interesting and add it to the corpus. Repeat.

#### **OUR SOLUTION: DEFINING A TEST**

- ➤ Main difference between Hw fuzzing and Sw fuzzing:
  - > Defining tests with timing.

- ➤ <u>Input</u>: Given a DUT with two 32b and one 64b input.
  - ➤ input size = 32 \* 2 + 64 = 128 bits
  - ➤ A single cycle of inputs is a bit-string of input\_size length.
  - ➤ Each line in the input file is a cycle's worth of inputs.

#### **OUR SOLUTION: MUTATION ENGINE**

- ➤ <u>1st attempt:</u> Direct use of AFL's engine using the JNI.
  - ➤ <u>Problem:</u> Compilation time was too long.
    - ➤ Need to add more dependencies (scala-jni).

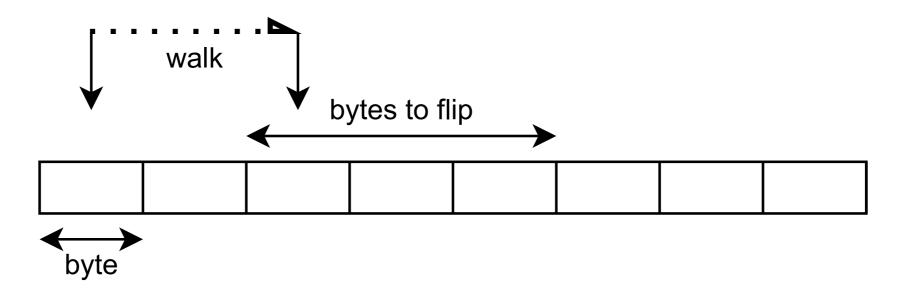
- > Solution: Reimplement subset of AFL's engine in Scala.
  - ➤ Use some deterministic mutation passes.
  - ➤ After that use non-deterministic passes.

> So far only deterministic passes have been implemented.

#### **OUR SOLUTION: MUTATION ENGINE**

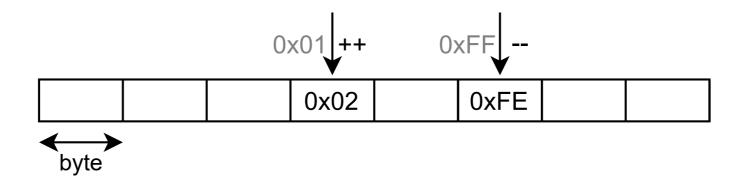
- Deterministic mutation passes:
  - ➤ <u>Walking bit-flips:</u> Sequentially walk through each input string line bit-by-bit and flip either 1, 2 or 4 bits/pass.

➤ Walking byte-flips: Same idea but byte-by-byte.

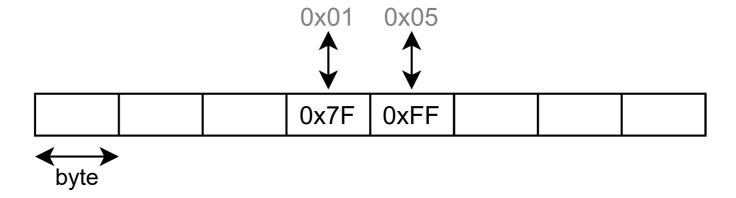


#### **OUR SOLUTION: MUTATION ENGINE**

➤ <u>Simple arithmetic:</u> Add or subtract values to each bit line. Done with multiple incrementation or decrementations of single bytes in the string.



➤ Known integers: Replace bytes in the string with predefined "interesting" integers like 0xFF or 0x7F.



## INITIAL EXPERIMENTS

#### INITIAL EXPERIMENTS: USE CASE

- ➤ <u>Note:</u> Our solution is a work in progress.
- ➤ <u>Use case:</u> Leros accumulator ALU:
  - ➤ Input op<3b>, din<8b>; Output out<8b>
  - ➤ <u>Goal:</u> Check for every operation using the most interesting operands.
- ➤ What we need to do:
  - ➤ 1) Create verification plan for functional coverage.
  - ➤ 2) Create input seed file.
  - ➤ 3) Run fuzzer.

#### INITIAL EXPERIMENTS: SETUP FUZZER

➤ <u>Verification plan:</u>

```
val cr = new CoverageReporter(dut)
cr.register(
  cover("op", dut.input.op)(
     bin("nop", 0 to 0),
     //[...] Bins for each operation
     bin("shr", 7 to 7)),
cover("din", dut.input.din)(
     bin("0xF", 0 to 0xF),
     //[...] Cover all ranges
     bin("0xFFFF", 0xFFF to 0xFFFF)),
cover("accu", dut.output.accu)(
     //[...] Same as din
cover("ena", dut.input.ena)(
     bin("disabled", 0 to 0),
     bin("enabled", 1 to 1)))
```

- <u>Call fuzzer:</u> Fuzzer(dut, cr)("output.txt", "seed.bin")

#### EVALUATION: IMPACT OF FUNCTIONAL COVERAGE ON EFFICIENCY

➤ Only initial tests have done so far and results aren't conclusive enough.

➤ Current work is being done on using the same fuzzer with edge coverage in order to compare the results to functional coverage.

➤ We **expect** functional coverage to lead to a converging fuzzer in less iterations than with edge coverage. However, the current efficiency of ChiselVerify's FC may also lead to slower fuzzing cycles.

## CONCLUSION

#### CONCLUSION

➤ Work-in-progress paper is a sketch of how to support testing and verification of digital designs described in Chisel with fuzzing.

➤ Basis for more detailed performance evaluation when all mutation techniques are added.

➤ Current work is being done on extending the fuzzing methods for constrained random code generation.

#### REFERENCES

- ➤ Kevin Laeufer, Jack Koenig, Donggyu Kim, Jonathan Bachrach, and Koushik Sen. **Rfuzz**: Coverage-directed fuzz testing of rtl on fpgas. In 2018 IEEE/ACM International Conference on Computer-Aided Design (ICCAD), pages 1–8, 2018.
- Michal Zalewski. American fuzzy lop. https://github.com/google/AFL.
- Timothy Trippel, Kang G. Shin, Alex Chernyakhovsky, Garret Kelly, Dominic Rizzo, and Matthew Hicks. **Fuzzing hardware like software**. CoRR, abs/2102.02308, 2021.
- ➤ Michal Zalewski. **Binary fuzzing strategies**: what works, what doesn't. https://lcamtuf.blogspot.com/2014/08/ binary- fuzzing- strategies- whatworks.html.

#### **GETTING STARTED USING CHISELVERIFY**

> Current Project repository:

https://github.com/chiselverify/chiselverify/

> Project Wiki (Good way to get started):

https://github.com/chiselverify/chiselverify/wiki/

➤ ChiselVerify is published on Maven. To use it, add following line to your build.sbt:

libraryDependencies += "io.github.chiselverify" % "chiselverify" % "0.1"

## QUESTIONS?